

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/616,696	SUGITA ET AL.
Examiner	Art Unit	
Dah-Wei D. Yuan	1745	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
429	12	7/11/2007	DWY
429	34	7/11/2007	DWY
429	38	7/11/2007	DWY